CE EMC TEST REPORT

Report No.: DDT-B22081803-1E01

Applicant	:	TPV Electronics (Fujian) Co., Ltd.
Address	:	Rongqiao Economic and Technological Development Zone, Fuqing City, Fujian Province, P.R. China
Equipment under Test	:	LCD Monitor
Model No.	:	**405******** ("*" = 0-9，A-Z，a-z，+，-，/，\ or blank)
Trade Mark	:	N/A

Issued By: Tianjin Dongdian Testing Service Co., Ltd.

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REPORT

CONTENTS

1. Summary of Test Results ... 7
2. General Test Information ... 8
2.1 Description of EUT ... 8
2.2 Primary Function of EUT ... 8
2.3 Port of EUT ... 9
2.4 Accessories of EUT ... 9
2.5 Test peripherals ... 9
2.6 Block diagram EUT configuration for test ... 10
2.7 EUT operating mode(s) ... 10
2.8 Performance Criteria ... 11
2.9 Deviations of test standard ... 11
2.10 Test laboratory ... 12
2.11 Measurement uncertainty ... 12
3. Conducted Emission (mains power port) ... 13
3.1 General information ... 13
3.2 Test Equipment ... 13
3.3 Reference standard ... 13
3.4 Block diagram of test setup ... 13
3.5 Limits ... 14
3.6 Test procedure ... 14
3.7 Test result ... 16
4. Conducted Emission (Telecommunication Port) ... 17
4.1 General information ... 17
4.2 Test equipment ... 17
4.3 Reference standard ... 17
4.4 Block diagram of test setup ... 17
4.5 Limits for conducted disturbance at the telecommunication ports ... 18
4.6 Test procedure ... 18
4.7 Test result ... 18
5. Radiated Emissions (30MHz to 1GHz) ... 19
5.1 General information ... 19
5.2 Test equipment ... 19
5.3 Reference standard ... 19
5.4 Block diagram of test setup ... 20
5.5 Limits ... 20
5.6 Test procedure ... 21
5.7 Test result ... 23
6. Radiated Emissions (Above 1GHz) ... 24
6.1 General information ... 24
6.2 Test equipment ... 24
6.3 Reference standard ... 24
6.4 Block diagram of test setup ... 25
6.5 Limits ... 25
6.6 Test procedure ... 25
6.7 Test result ... 27
7. Harmonics current ... 28
7.1 General information ... 28
7.2 Test equipment ... 28
7.3 Reference standard ... 28
7.4 Block diagram of test setup ... 28
7.5 Limits ... 29
7.6 Test result ... 29
8. Voltage fluctuation & Flicker ... 32
8.1 General information ... 32
8.2 Test equipment ... 32
8.3 Reference standard ... 32
8.4 Block diagram of test setup ... 33

8.5 Limits 33
8.6 Test result 33
9. Electrostatic Discharge 35
9.1 General information 35
9.2 Test equipment 35
9.3 Test and reference standards 35
9.4 Block diagram of test setup 35
9.5 Test levels and performance criterion 36
9.6 Test procedure 36
9.7 Test result 37
10. Continuous Radio Frequency Disturbances 39
10.1 General information 39
10.2 Test equipment 39
10.3 Test and reference standards 39
10.4 Block diagram of test setup 39
10.5 Test levels and performance criterion 40
10.6 Test procedure 41
10.7 Test result 41
11. Electrical Fast Transients (EFT) 42
11.1 General information 42
11.2 Test equipment 42
11.3 Test and reference standards 42
11.4 Block diagram of test setup 42
11.5 Test levels and performance criterion 43
11.6 Test Procedure 43
11.7 Test result 44
12. Surges 45
12.1 General information 45
12.2 Test equipment 45
12.3 Test and reference standards 45
12.4 Block diagram of test setup 45
12.5 Test levels and performance criterion 46
12.6 Test Procedure 46
12.7 Test result 47
13. Continuous Conducted Disturbances 48
13.1 General information 48
13.2 Test Equipment 48
13.3 Test and reference standards 48
13.4 Block diagram of test setup 48
13.5 Test levels and performance criterion 49
13.6 Test procedure 50
13.7 Test result 50
14. Power-Frequency Magnetic Fields 51
14.1 General information 51
14.2 Test equipment 51
14.3 Test and reference standards 51
14.4 Block diagram of test setup 51
14.5 Test levels and performance criterion 52
14.6 Test procedure 52
14.7 Test result 52
15. Voltage Dips and Interruptions 53
15.1 General information 53
15.2 Test equipment 53
15.3 Test and reference standards 53
15.4 Block diagram of test setup 53
15.5 Test levels and performance criterion 53
15.6 Test procedure 54
15.7 Test result 54

Annex A Test Setup Photos 55

Test Report Declare

Applicant	:	TPV Electronics (Fujian) Co., Ltd.
Address	:	Rongqiao Economic and Technological Development Zone, Fuqing City, Fujian Province, P.R. China
Equipment Under Test	:	LCD Monitor
Model No.	:	**405******** (“*” = 0-9，A-Z，A-Z，+，-，/，\ OR BLANK)
Trade Mark	:	N/A

Test Standard Used:
EN 55032:2015, EN 55032:2015/A11:2020, EN 55032:2015/A1:2020,
CISPR 32:2015/AMD1:2019, AS/NZS CISPR 32:2015 AMD 1:2020
BS EN 55032:2015, BS EN 55032:2015+A11:2020, BS EN 55032:2015+A1:2020
EN 55035:2017, EN 55035:2017/A11:2020, CISPR 35:2016, BS EN 55035:2017
BS EN 55035:2017+A11:2020
EN 61000-3-2:2014, EN IEC 61000-3-2:2019/A1:2021, BS EN 61000-3-2:2014, BS EN IEC 61000-3-2:2019+A1:2021
EN 61000-3-3:2013, EN 61000-3-3:2013/A1:2019, EN 61000-3-3:2013/A2:2021, BS EN 61000-3-3:2013, BS EN 61000-3-3:2013+A1:2019, BS EN 61000-3-3:2013/A2:2021

Test Procedure Used:
IEC 61000-4-2:2008, IEC 61000-4-3:2020, IEC 61000-4-4:2012,
IEC 61000-4-5:2014/AMD1:2017, IEC 61000-4-6:2013, IEC 61000-4-8:2009, IEC 61000-4-11:2020

We Declare:
The equipment described above is tested and assessed by Tianjin Dongdian Testing Service Co., Ltd. and in the configuration assessed the equipment complied with the standards specified above. The tested and assessed results are contained in this test report and Tianjin Dongdian Testing Service Co., Ltd. is assumed of full responsibility for the accuracy and completeness of these assessments.
After test and evaluation, our opinion is that the equipment in accordance with above standards.

Report No.:	DDT-B22081803-1E01		
Date of Receipt:	Aug. 19, 2022	Date of Test:	Aug. 21, 2022 ~ Sep. 05, 2022

Prepared By:
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Approved By:
Aaron Zhang
Aaron Zhang/EMC Manager

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The report must not be used by the client to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the U.S. Government.

Revision History

Rev.	Revisions	Issue Date	Revised By
---	Initial issue	Sep. 12, 2022	